

<b>Notice of References Cited</b>	Application/Control No. 10/671,025	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Chuck Huynh	Art Unit 2683	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,159,632	12-2000	Osawa, Takahisa	429/100
	B	US-2002/0024794	02-2002	Lin et al.	361/686
	C	US-6,712,643	03-2004	Suzuki, Shinji	439/500
	D	US-6,730,432	05-2004	Grosfeld et al.	429/97
	E	US-6,898,074	05-2005	Hsu et al.	361/679
	F	US-2005/0086982	04-2005	Nakazima et al.	070/214
	G	US-2004/0132319	07-2004	Richter et al.	439/066
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	KR 010068980	07-2001	Korea	Lee, Jeong Cheol	H04B 1/38
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.